Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/646,708	ECKER ET AL.	
Examiner	Art Unit	
Patrick J. Lee	2878	

SEARCHED					
Class	Subclass	Date	Examiner		
250	227.14, 227.16	12/12/2005	PL		
385	10, 12	12/12/2005	PL		
385	13, 37	12/12/2005	PL		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	<u> </u>			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Consulted w/ S. Allen	8/4/2005	PL	
Consulted w/ B. Healy AU 2883 CL 385	8/9/2005	PL	
East (See attached)	8/9/2005	PL	
East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	12/12/2005	PL	